



Form 1449 (Modified)	Atty Docket No. LAM1P182/P1183	Application No.: 10/712,410
Information Disclosure Statement By Applicant	Applicant: Waggner et al.	
	Filing Date November 12, 2003	Group 2818
(Use Several Sheets if Necessary)		

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
PD	A	5,658,425	08/19/97	Halman et al.	438	620	06/07/95
PD	B	6,080,680	06/27/00	Lee et al.	438	727	12/19/97
PD	C	6,090,304	07/18/00	Zhu et al.	216	79	08/28/97
PD	D	6,518,174B2	02/11/03	Annapragada et al.	438	637	12/22/00
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
PD	O	Calvin T. Gabriel, et al., "Measuring and Minimizing Line Edge Roughness in BEOL Damascene Dielectric Patterning", 2003 AVS 4th Int'l. Conf. on Microelectronics and Interfaces, March 3-6, Santa Clara, CA, pages 204-207.
	P	
	Q	
Examiner PHUC T. DANG		Date Considered 1/29/05

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.